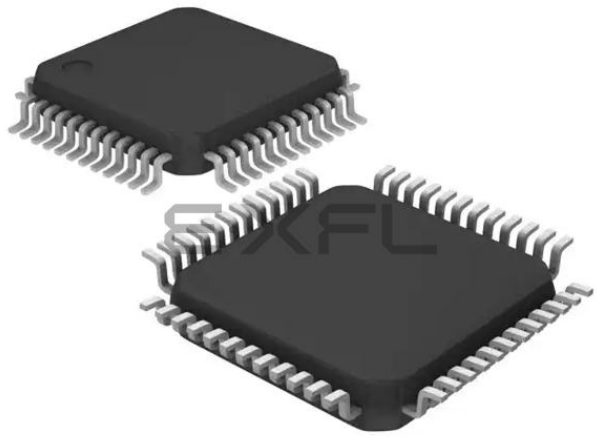

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"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Active
Core Processor	ARM® Cortex®-M0
Core Size	32-Bit Single-Core
Speed	50MHz
Connectivity	I²C, Microwire, SPI, SSI, SSP, UART/USART
Peripherals	Brown-out Detect/Reset, POR, WDT
Number of I/O	40
Program Memory Size	24KB (24K x 8)
Program Memory Type	FLASH
EEPROM Size	2K x 8
RAM Size	8K x 8
Voltage - Supply (Vcc/Vdd)	1.8V ~ 3.6V
Data Converters	A/D 8x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	48-LQFP
Supplier Device Package	48-LQFP (7x7)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/lpc11e13fbd48-301

Table 3. Pin description

Symbol	HVQFN33	LQFP48	LQFP64		Reset state [1]	Type	Description
PIO1_23/CT16B1_MAT1/ SSEL1	13	18	24	[3]	I; PU	I/O	**PIO1_23 —** General purpose digital input/output pin.
					-	O	**CT16B1_MAT1 —** Match output 1 for 16-bit timer 1.
					-	I/O	**SSEL1 —** Slave select for SSP1.
PIO1_24/CT32B0_MAT0	14	21	27	[3]	I; PU	I/O	**PIO1_24 —** General purpose digital input/output pin.
					-	O	**CT32B0_MAT0 —** Match output 0 for 32-bit timer 0.
PIO1_25/CT32B0_MAT1	-	1	2	[3]	I; PU	I/O	**PIO1_25 —** General purpose digital input/output pin.
					-	O	**CT32B0_MAT1 —** Match output 1 for 32-bit timer 0.
PIO1_26/CT32B0_MAT2/ RXD	-	11	14	[3]	I; PU	I/O	**PIO1_26 —** General purpose digital input/output pin.
					-	O	**CT32B0_MAT2 —** Match output 2 for 32-bit timer 0.
					-	I	**RXD —** Receiver input for USART.
PIO1_27/CT32B0_MAT3/ TXD	-	12	15	[3]	I; PU	I/O	**PIO1_27 —** General purpose digital input/output pin.
					-	O	**CT32B0_MAT3 —** Match output 3 for 32-bit timer 0.
					-	O	**TXD —** Transmitter output for USART.
PIO1_28/CT32B0_CAP0/ SCLK	-	24	31	[3]	I; PU	I/O	**PIO1_28 —** General purpose digital input/output pin.
					-	I	**CT32B0_CAP0 —** Capture input 0 for 32-bit timer 0.
					-	I/O	**SCLK —** Serial clock input/output for USART in synchronous mode.
PIO1_29/SCK0/ CT32B0_CAP1	-	31	41	[3]	I; PU	I/O	**PIO1_29 —** General purpose digital input/output pin.
					-	I/O	**SCK0 —** Serial clock for SSP0.
					-	I	**CT32B0_CAP1 —** Capture input 1 for 32-bit timer 0.
PIO1_31	-	25	-	[3]	I; PU	I/O	**PIO1_31 —** General purpose digital input/output pin.
n.c.	-	19	25		F	-	Not connected.
n.c.	-	20	26		F	-	Not connected.
XTALIN	4	6	8	[7]	-	-	Input to the oscillator circuit and internal clock generator circuits. Input voltage must not exceed 1.8 V.
XTALOUT	5	7	9	[7]	-	-	Output from the oscillator amplifier.
V_{DD}	6; 29	8; 44	10; 33; 48; 58		-	-	Supply voltage to the internal regulator, the external rail, and the ADC. Also used as the ADC reference voltage.
V_{SS}	33	5; 41	7; 54		-	-	Ground.

[1] Pin state at reset for default function: I = Input; O = Output; PU = internal pull-up enabled; IA = inactive, no pull-up/down enabled; F = floating; If the pins are not used, tie floating pins to ground or power to minimize power consumption.

[2] 5 V tolerant pad. $\overline{\text{RESET}}$ functionality is not available in Deep power-down mode. Use the WAKEUP pin to reset the chip and wake up from Deep power-down mode. An external pull-up resistor is required on this pin for the Deep power-down mode. See Figure 28 for the reset pad configuration.

[3] 5 V tolerant pad providing digital I/O functions with configurable pull-up/pull-down resistors and configurable hysteresis (see Figure 27).

[4] I^2C-bus pins compliant with the I^2C-bus specification for I^2C standard mode, I^2C Fast-mode, and I^2C Fast-mode Plus.

[5] 5 V tolerant pad providing digital I/O functions with configurable pull-up/pull-down resistors and configurable hysteresis (see Figure 27); includes high-current output driver.

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[6] 5 V tolerant pad providing digital I/O functions with configurable pull-up/pull-down resistors, configurable hysteresis, and analog input. When configured as a ADC input, digital section of the pad is disabled and the pin is not 5 V tolerant (see Figure 27); includes digital input glitch filter.

[7] When the system oscillator is not used, connect XTALIN and XTALOUT as follows: XTALIN can be left floating or can be grounded (grounding is preferred to reduce susceptibility to noise). Leave XTALOUT floating.

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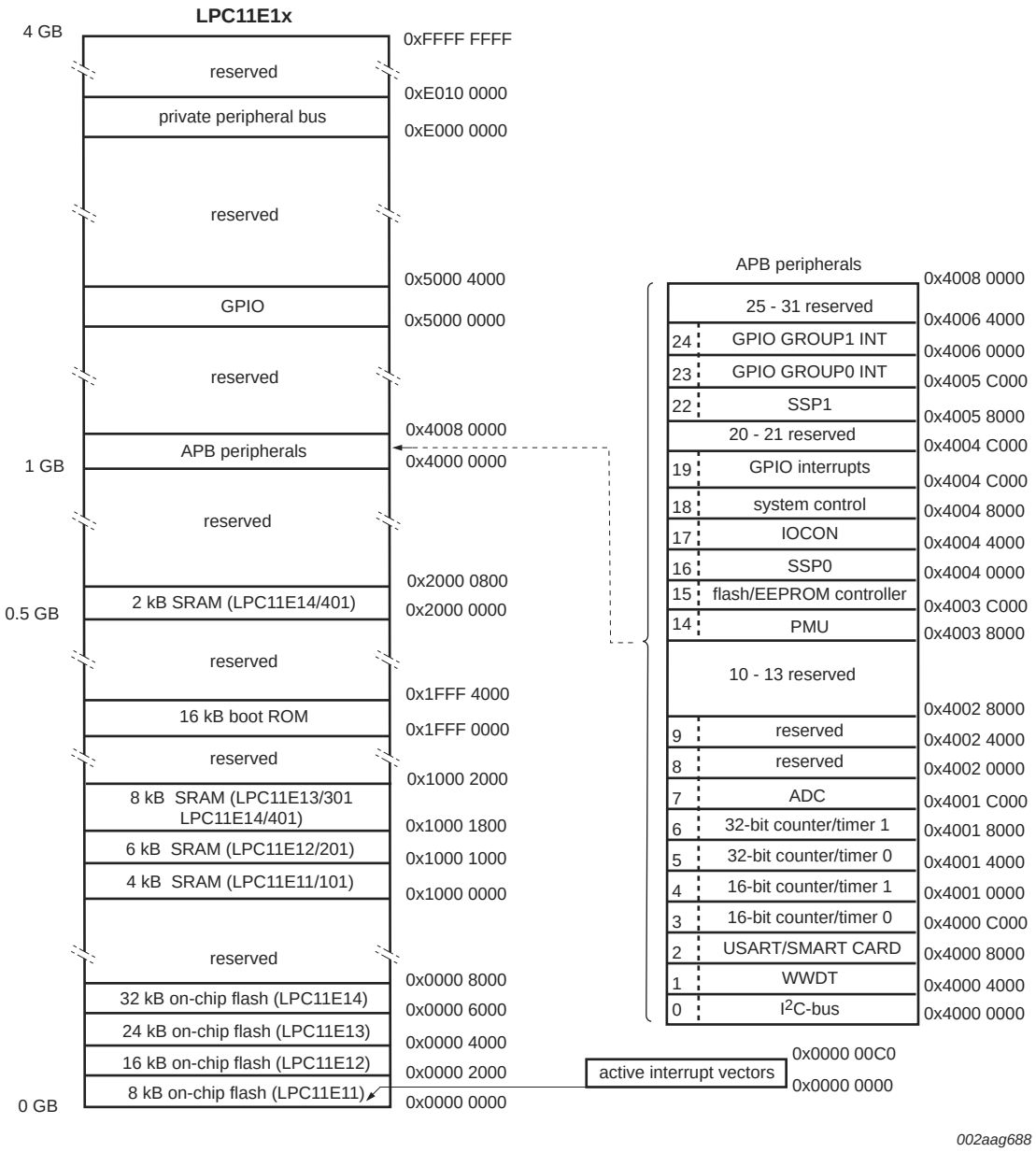

Fig 5. LPC11E1x memory map

7.6 Nested Vectored Interrupt Controller (NVIC)

The Nested Vectored Interrupt Controller (NVIC) is part of the Cortex-M0. The tight coupling to the CPU allows for low interrupt latency and efficient processing of late arriving interrupts.

7.6.1 Features

- Controls system exceptions and peripheral interrupts.
- In the LPC11E1x, the NVIC supports 24 vectored interrupts.

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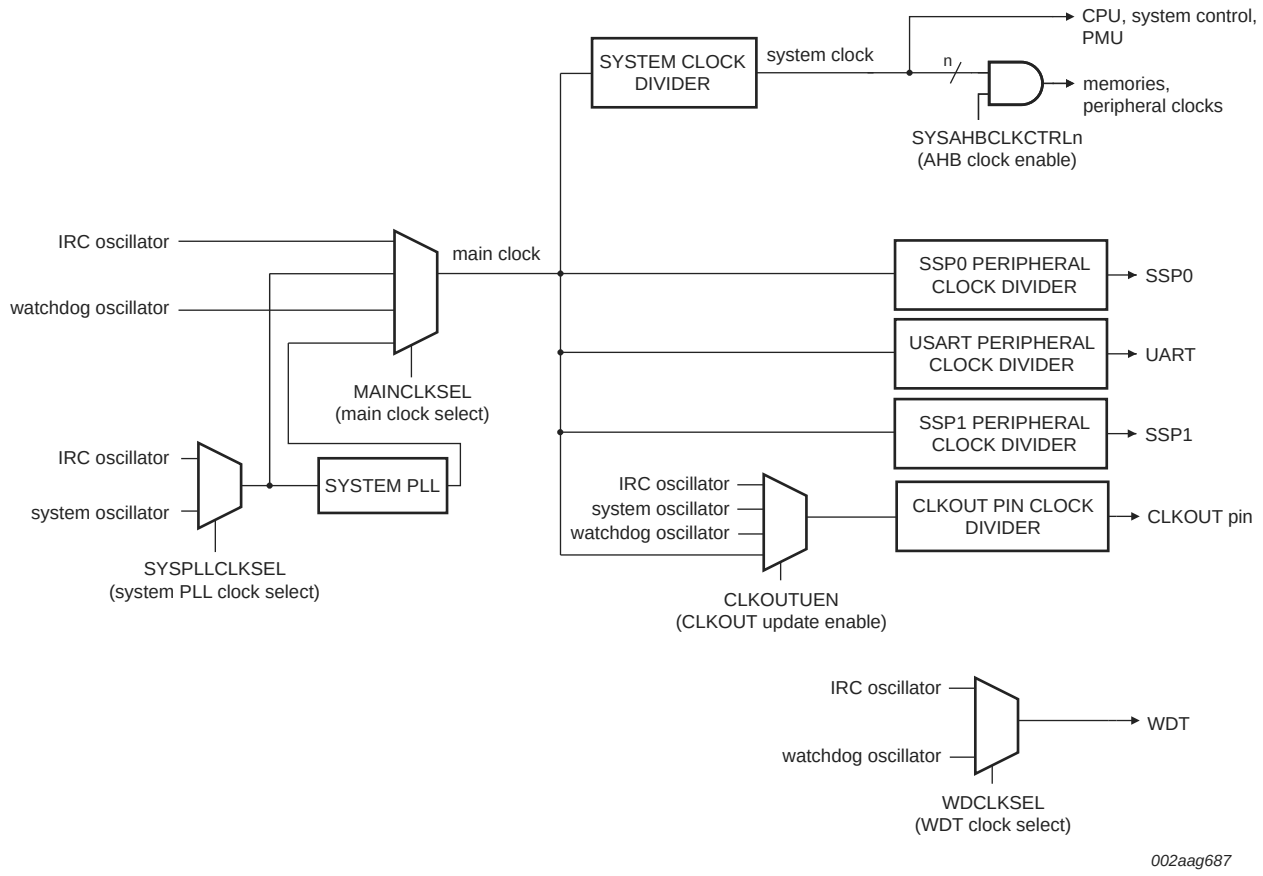

Fig 6. LPC11E1x clocking generation block diagram

7.16.1.1 Internal RC oscillator

The IRC can be used as the clock source for the WDT, and/or as the clock that drives the system PLL and then the CPU. The nominal IRC frequency is 12 MHz.

Upon power-up, any chip reset, or wake-up from Deep power-down mode, the LPC11E1x use the IRC as the clock source. Software can later switch to one of the other available clock sources.

7.16.1.2 System oscillator

The system oscillator can be used as the clock source for the CPU, with or without using the PLL.

The system oscillator operates at frequencies of 1 MHz to 25 MHz. This frequency can be boosted to a higher frequency, up to the maximum CPU operating frequency, by the system PLL.

7.16.1.3 Watchdog oscillator

The watchdog oscillator can be used as a clock source that directly drives the CPU, the watchdog timer, or the CLKOUT pin. The watchdog oscillator nominal frequency is programmable between 7.8 kHz and 1.7 MHz. The frequency spread over processing and temperature is ±40 % (see also Table 13).

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7.16.5.2 Sleep mode

When Sleep mode is entered, the clock to the core is stopped. Resumption from the Sleep mode does not need any special sequence but re-enabling the clock to the ARM core.

In Sleep mode, execution of instructions is suspended until either a reset or interrupt occurs. Peripheral functions continue operation during Sleep mode and can generate interrupts to cause the processor to resume execution. Sleep mode eliminates dynamic power used by the processor itself, by memory systems and related controllers, and by internal buses.

7.16.5.3 Deep-sleep mode

In Deep-sleep mode, the LPC11E1x is in Sleep-mode and all peripheral clocks and all clock sources are off except for the IRC. The IRC output is disabled unless the IRC is selected as input to the watchdog timer. In addition all analog blocks are shut down and the flash is in stand-by mode. In Deep-sleep mode, the application can keep the watchdog oscillator and the BOD circuit running for self-timed wake-up and BOD protection.

The LPC11E1x can wake up from Deep-sleep mode via reset, selected GPIO pins, or a watchdog timer interrupt.

Deep-sleep mode saves power and allows for short wake-up times.

7.16.5.4 Power-down mode

In Power-down mode, the LPC11E1x is in Sleep-mode and all peripheral clocks and all clock sources are off except for watchdog oscillator if selected. In addition all analog blocks and the flash are shut down. In Power-down mode, the application can keep the BOD circuit running for BOD protection.

The LPC11E1x can wake up from Power-down mode via reset, selected GPIO pins, or a watchdog timer interrupt.

Power-down mode reduces power consumption compared to Deep-sleep mode at the expense of longer wake-up times.

7.16.5.5 Deep power-down mode

In Deep power-down mode, power is shut off to the entire chip except for the WAKEUP pin. The LPC11E1x can wake up from Deep power-down mode via the WAKEUP pin.

The LPC11E1x can be prevented from entering Deep power-down mode by setting a lock bit in the PMU block. Locking out Deep power-down mode enables the application to keep the watchdog timer or the BOD running at all times.

When entering Deep power-down mode, an external pull-up resistor is required on the WAKEUP pin to hold it HIGH. Pull the $\overline{\text{RESET}}$ pin HIGH to prevent it from floating while in Deep power-down mode.

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CAUTION

If level three Code Read Protection (CRP3) is selected, no future factory testing can be performed on the device.

In addition to the three CRP levels, sampling of pin PIO0_1 for valid user code can be disabled. For details, see the *LPC11Exx user manual*.

7.16.6.4 APB interface

The APB peripherals are located on one APB bus.

7.16.6.5 AHBLite

The AHBLite connects the CPU bus of the ARM Cortex-M0 to the flash memory, the main static RAM, and the ROM.

7.16.6.6 External interrupt inputs

All GPIO pins can be level or edge sensitive interrupt inputs.

7.17 Emulation and debugging

Debug functions are integrated into the ARM Cortex-M0. Serial wire debug functions are supported in addition to a standard JTAG boundary scan. The ARM Cortex-M0 is configured to support up to four breakpoints and two watch points.

The $\overline{\text{RESET}}$ pin selects between the JTAG boundary scan ($\overline{\text{RESET}}$ = LOW) and the ARM SWD debug ($\overline{\text{RESET}}$ = HIGH). The ARM SWD debug port is disabled while the LPC11E1x is in reset.

To perform boundary scan testing, follow these steps:

1. Erase any user code residing in flash.
2. Power up the part with the $\overline{\text{RESET}}$ pin pulled HIGH externally.
3. Wait for at least 250 μs.
4. Pull the $\overline{\text{RESET}}$ pin LOW externally.
5. Perform boundary scan operations.
6. Once the boundary scan operations are completed, assert the $\overline{\text{TRST}}$ pin to enable the SWD debug mode, and release the $\overline{\text{RESET}}$ pin (pull HIGH).

Remark: The JTAG interface cannot be used for debug purposes.

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8. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).[1]

Symbol	Parameter	Conditions		Min	Max	Unit
V_{DD}	supply voltage (core and external rail)		[2]	–0.5	+4.6	V
V_I	input voltage	5 V tolerant digital I/O pins; $V_{DD} \geq 1.8$ V	[5][2]	–0.5	+5.5	V
		$V_{DD} = 0$ V		–0.5	+3.6	V
		5 V tolerant open-drain pins PIO0_4 and PIO0_5	[2][4]	–0.5	+5.5	
V_{IA}	analog input voltage	pin configured as analog input	[2] [3]	–0.5	4.6	V
I_{DD}	supply current	per supply pin		-	100	mA
I_{SS}	ground current	per ground pin		-	100	mA
I_{latch}	I/O latch-up current	$-(0.5V_{DD}) < V_I < (1.5V_{DD})$; $T_j < 125$ °C		-	100	mA
T_{stg}	storage temperature	non-operating	[6]	–65	+150	°C
$T_{j(max)}$	maximum junction temperature			-	150	°C
$P_{tot(pack)}$	total power dissipation (per package)	based on package heat transfer, not device power consumption		-	1.5	W
V_{ESD}	electrostatic discharge voltage	human body model; all pins	[7]	-	+6500	V

[1] The following applies to the limiting values:

a) This product includes circuitry specifically designed for the protection of its internal devices from the damaging effects of excessive static charge. Nonetheless, it is suggested that conventional precautions be taken to avoid applying greater than the rated maximum.

b) Parameters are valid over operating temperature range unless otherwise specified. All voltages are with respect to V_{SS} unless otherwise noted.

c) The limiting values are stress ratings only. Operating the part at these values is not recommended, and proper operation is not guaranteed. The conditions for functional operation are specified in Table 5.

[2] Maximum/minimum voltage above the maximum operating voltage (see Table 5) and below ground that can be applied for a short time (< 10 ms) to a device without leading to irrecoverable failure. Failure includes the loss of reliability and shorter lifetime of the device.

[3] See Table 6 for maximum operating voltage.

[4] V_{DD} present or not present. Compliant with the I^2C-bus standard. 5.5 V can be applied to this pin when V_{DD} is powered down.

[5] Including voltage on outputs in 3-state mode.

[6] The maximum non-operating storage temperature is different than the temperature for required shelf life which should be determined based on required shelf lifetime. Please refer to the JEDEC spec (J-STD-033B.1) for further details.

[7] Human body model: equivalent to discharging a 100 pF capacitor through a 1.5 kΩ series resistor.

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9. Static characteristics

Table 5. Static characteristics

T_{amb} = −40 °C to +85 °C, unless otherwise specified.

Symbol	Parameter	Conditions		Min	Typ[1]	Max	Unit
V_{DD}	supply voltage (core and external rail)			1.8	3.3	3.6	V
I_{DD}	supply current	Active mode; V_{DD} = 3.3 V; T_{amb} = 25 °C; code `while(1){}` executed from flash;					
		system clock = 12 MHz	[2][3][4][5][6]	-	2	-	mA
		system clock = 50 MHz	[3][4][5][6][7]	-	7	-	mA
		Sleep mode; V_{DD} = 3.3 V; T_{amb} = 25 °C; system clock = 12 MHz	[2][3][4][5][6]	-	1	-	mA
		Deep-sleep mode; V_{DD} = 3.3 V; T_{amb} = 25 °C	[3]	-	360	-	μA
		Power-down mode; V_{DD} = 3.3 V; T_{amb} = 25 °C		-	2	-	μA
		Deep power-down mode; V_{DD} = 3.3 V; T_{amb} = 25 °C	[8]	-	220	-	nA
Standard port pins, $\overline{\text{RESET}}$							
I_{IL}	LOW-level input current	V_I = 0 V; on-chip pull-up resistor disabled		-	0.5	10	nA
I_{IH}	HIGH-level input current	V_I = V_{DD}; on-chip pull-down resistor disabled		-	0.5	10	nA
I_{OZ}	OFF-state output current	V_O = 0 V; V_O = V_{DD}; on-chip pull-up/down resistors disabled		-	0.5	10	nA
V_I	input voltage	pin configured to provide a digital function	[9][10][11]	0	-	5.0	V
V_O	output voltage	output active		0	-	V_{DD}	V
V_{IH}	HIGH-level input voltage			$0.7V_{DD}$	-	-	V
V_{IL}	LOW-level input voltage			-	-	$0.3V_{DD}$	V
V_{hys}	hysteresis voltage			-	0.4	-	V
V_{OH}	HIGH-level output voltage	2.0 V ≤ V_{DD} ≤ 3.6 V; I_{OH} = −4 mA		V_{DD} − 0.4	-	-	V
		1.8 V ≤ V_{DD} < 2.0 V; I_{OH} = −3 mA		V_{DD} − 0.4	-	-	V
V_{OL}	LOW-level output voltage	2.0 V ≤ V_{DD} ≤ 3.6 V; I_{OL} = 4 mA		-	-	0.4	V
		1.8 V ≤ V_{DD} < 2.0 V; I_{OL} = 3 mA		-	-	0.4	V
I_{OH}	HIGH-level output current	V_{OH} = V_{DD} − 0.4 V; 2.0 V ≤ V_{DD} ≤ 3.6 V		−4	-	-	mA
		1.8 V ≤ V_{DD} < 2.0 V		−3	-	-	mA

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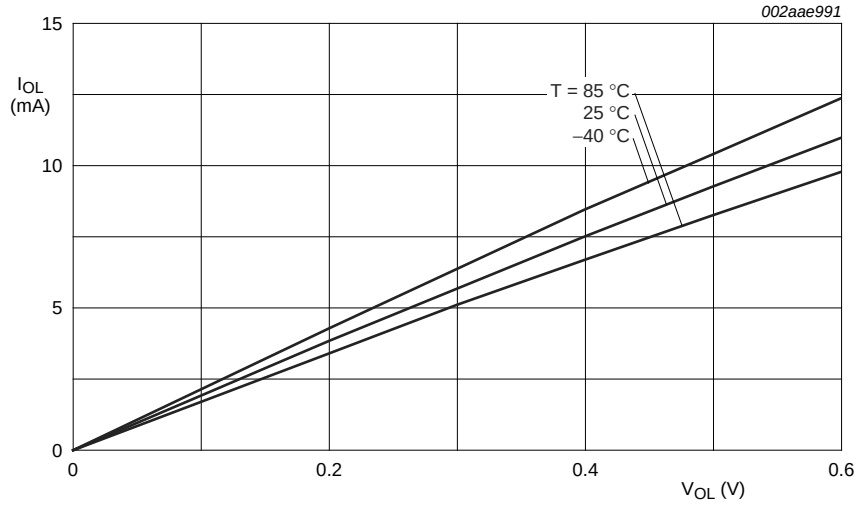
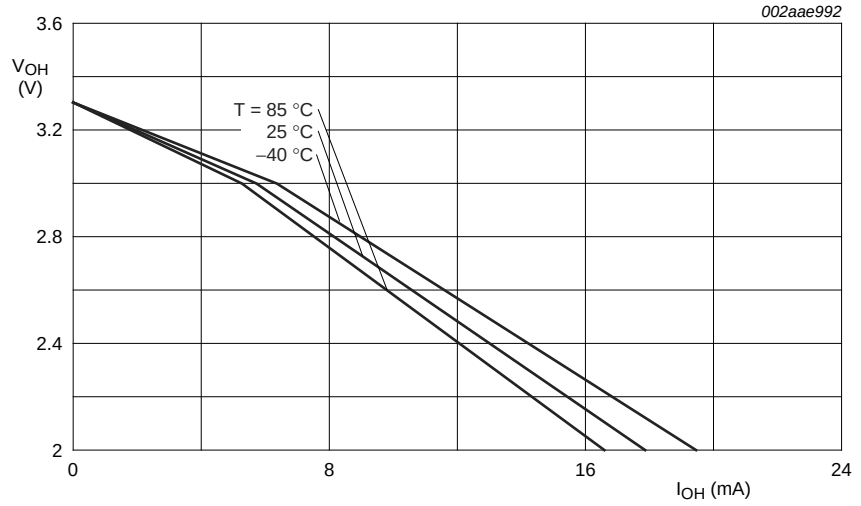


Conditions: V_{DD} = 3.3 V; standard port pins and PIO0_7.

Fig 16. Typical LOW-level output current I_{OL} versus LOW-level output voltage V_{OL}



Conditions: V_{DD} = 3.3 V; standard port pins.

Fig 17. Typical HIGH-level output voltage V_{OH} versus HIGH-level output source current I_{OH}

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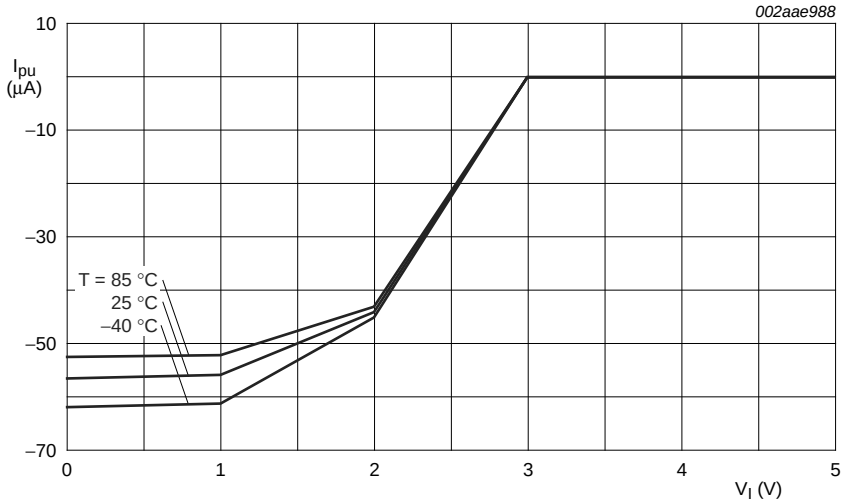
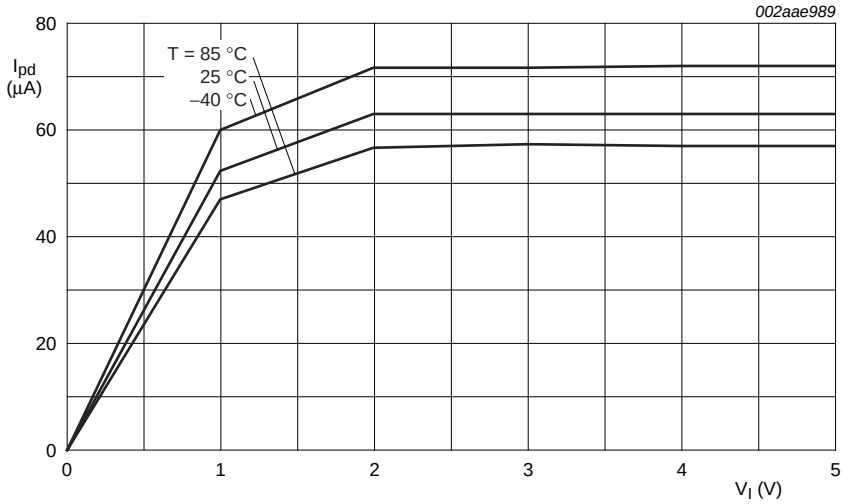


Conditions: V_{DD} = 3.3 V; standard port pins.

Fig 18. Typical pull-up current I_{pu} versus input voltage V_I



Conditions: V_{DD} = 3.3 V; standard port pins.

Fig 19. Typical pull-down current I_{pd} versus input voltage V_I

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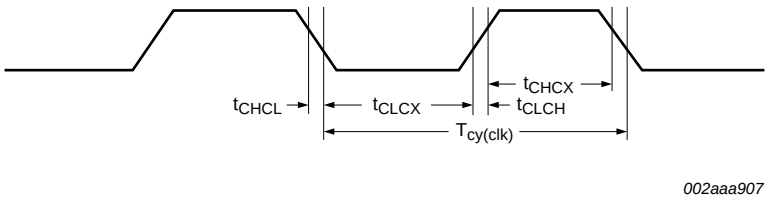


Fig 20. External clock timing (with an amplitude of at least $V_{i(RMS)}$ = 200 mV)

10.3 Internal oscillators

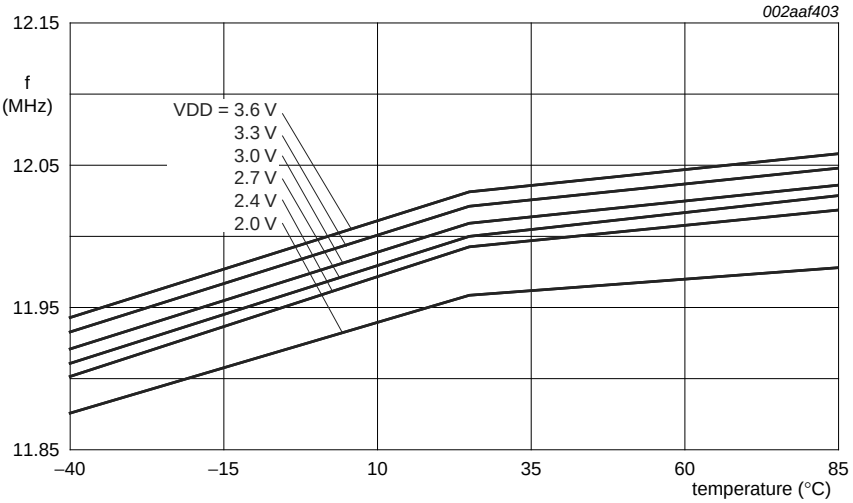
Table 12. Dynamic characteristics: IRC

T_{amb} = −40 °C to +85 °C; 2.7 V ≤ V_{DD} ≤ 3.6 V[1].

Symbol	Parameter	Conditions	Min	Typ[2]	Max	Unit
$f_{osc(RC)}$	internal RC oscillator frequency	-	11.88	12	12.12	MHz

[1] Parameters are valid over operating temperature range unless otherwise specified.

[2] Typical ratings are not guaranteed. The values listed are at room temperature (25 °C), nominal supply voltages.



Conditions: Frequency values are typical values. 12 MHz ± 1 % accuracy is guaranteed for 2.7 V ≤ V_{DD} ≤ 3.6 V and T_{amb} = −40 °C to +85 °C. Variations between parts may cause the IRC to fall outside the 12 MHz ± 1 % accuracy specification for voltages below 2.7 V.

Fig 21. Internal RC oscillator frequency versus temperature

Table 13. Dynamic characteristics: Watchdog oscillator

Symbol	Parameter	Conditions		Min	Typ[1]	Max	Unit
$f_{osc(int)}$	internal oscillator frequency	DIVSEL = 0x1F, FREQSEL = 0x1 in the WDTOSCCTRL register;	[2][3]	-	7.8	-	kHz
		DIVSEL = 0x00, FREQSEL = 0xF in the WDTOSCCTRL register	[2][3]	-	1700	-	kHz

[1] Typical ratings are not guaranteed. The values listed are at nominal supply voltages.

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[2] The typical frequency spread over processing and temperature (T_{amb} = −40 °C to +85 °C) is ±40 %.

[3] See the *LPC11Exx user manual.*

10.4 I/O pins

Table 14. Dynamic characteristics: I/O pins[1]
T_{amb} = −40 °C to +85 °C; 3.0 V ≤ V_{DD} ≤ 3.6 V.

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
t_r	rise time	pin configured as output	3.0	-	5.0	ns
t_f	fall time	pin configured as output	2.5	-	5.0	ns

[1] Applies to standard port pins and $\overline{\text{RESET}}$ pin.

10.5 I²C-bus

Table 15. Dynamic characteristic: I²C-bus pins[1]
T_{amb} = −40 °C to +85 °C.[2]

Symbol	Parameter		Conditions	Min	Max	Unit
f_{SCL}	SCL clock frequency		Standard-mode	0	100	kHz
			Fast-mode	0	400	kHz
			Fast-mode Plus	0	1	MHz
t_f	fall time	[4][5][6][7]	of both SDA and SCL signals	-	300	ns
			Standard-mode			
			Fast-mode	20 + 0.1 × C_b	300	ns
			Fast-mode Plus	-	120	ns
t_{LOW}	LOW period of the SCL clock		Standard-mode	4.7	-	µs
			Fast-mode	1.3	-	µs
			Fast-mode Plus	0.5	-	µs
t_{HIGH}	HIGH period of the SCL clock		Standard-mode	4.0	-	µs
			Fast-mode	0.6	-	µs
			Fast-mode Plus	0.26	-	µs
$t_{HD;DAT}$	data hold time	[3][4][8]	Standard-mode	0	-	µs
			Fast-mode	0	-	µs
			Fast-mode Plus	0	-	µs
$t_{SU;DAT}$	data set-up time	[9][10]	Standard-mode	250	-	ns
			Fast-mode	100	-	ns
			Fast-mode Plus	50	-	ns

[1] See the I²C-bus specification *UM10204* for details.

[2] Parameters are valid over operating temperature range unless otherwise specified.

[3] tHD;DAT is the data hold time that is measured from the falling edge of SCL; applies to data in transmission and the acknowledge.

[4] A device must internally provide a hold time of at least 300 ns for the SDA signal (with respect to the V_{IH}(min) of the SCL signal) to bridge the undefined region of the falling edge of SCL.

[5] C_b = total capacitance of one bus line in pF.

[6] The maximum t_f for the SDA and SCL bus lines is specified at 300 ns. The maximum fall time for the SDA output stage t_f is specified at 250 ns. This allows series protection resistors to be connected in between the SDA and the SCL pins and the SDA/SCL bus lines without exceeding the maximum specified t_f.

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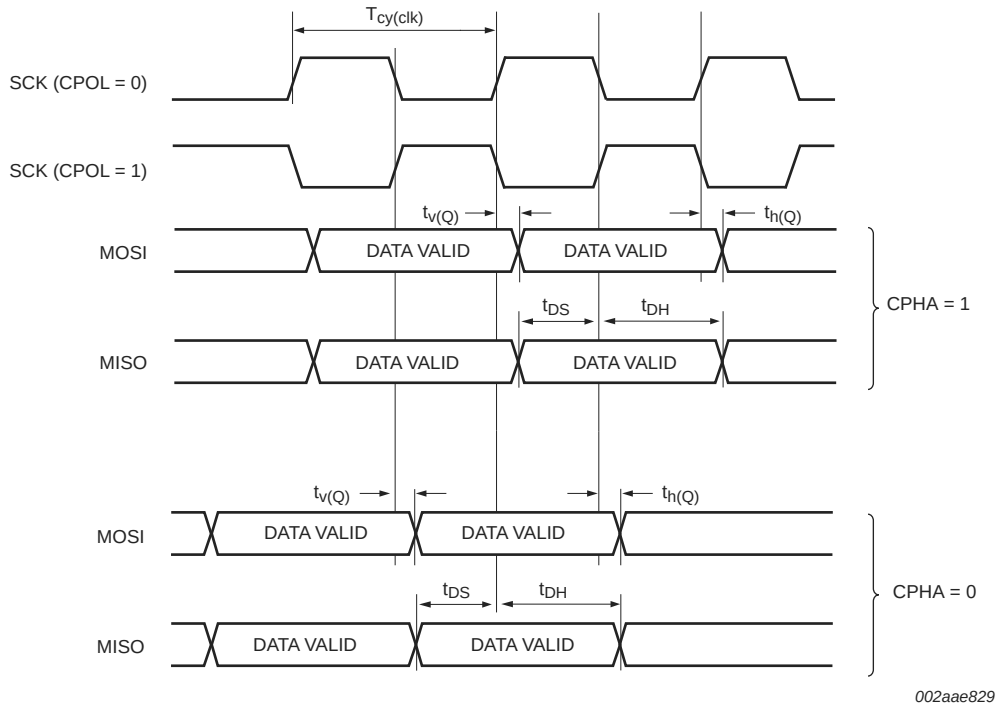

Fig 23. SSP master timing in SPI mode

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11. Application information

11.1 XTAL input

The input voltage to the on-chip oscillators is limited to 1.8 V. If the oscillator is driven by a clock in slave mode, it is recommended that the input be coupled through a capacitor with C_i = 100 pF. To limit the input voltage to the specified range, choose an additional capacitor to ground C_g which attenuates the input voltage by a factor $C_i/(C_i + C_g)$. In slave mode, a minimum of 200 mV(RMS) is needed.

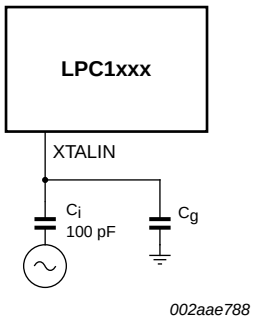

Fig 25. Slave mode operation of the on-chip oscillator

In slave mode, couple the input clock signal with a capacitor of 100 pF (Figure 25), with an amplitude between 200 mV(RMS) and 1000 mV(RMS). This signal corresponds to a square wave signal with a signal swing of between 280 mV and 1.4 V. The XTALOUT pin in this configuration can be left unconnected.

External components and models used in oscillation mode are shown in Figure 26 and in Table 17 and Table 18. Since the feedback resistance is integrated on chip, only a crystal and the capacitances C_{X1} and C_{X2} need to be connected externally in case of fundamental mode oscillation (L, C_L and R_S represent the fundamental frequency). Capacitance C_P in Figure 26 represents the parallel package capacitance and must not be larger than 7 pF. Parameters F_{OSC}, C_L, R_S and C_P are supplied by the crystal manufacturer.

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11.4 Reset pad configuration

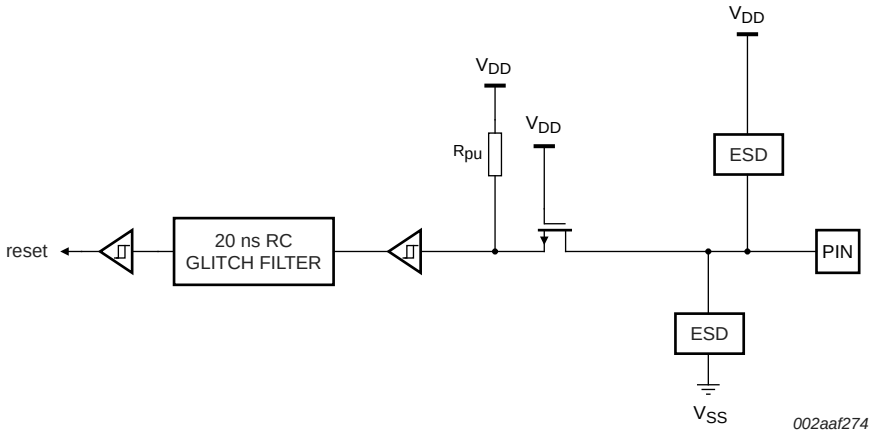

Fig 28. Reset pad configuration

11.5 ADC effective input impedance

A simplified diagram of the ADC input channels can be used to determine the effective input impedance seen from an external voltage source. See Figure 29.

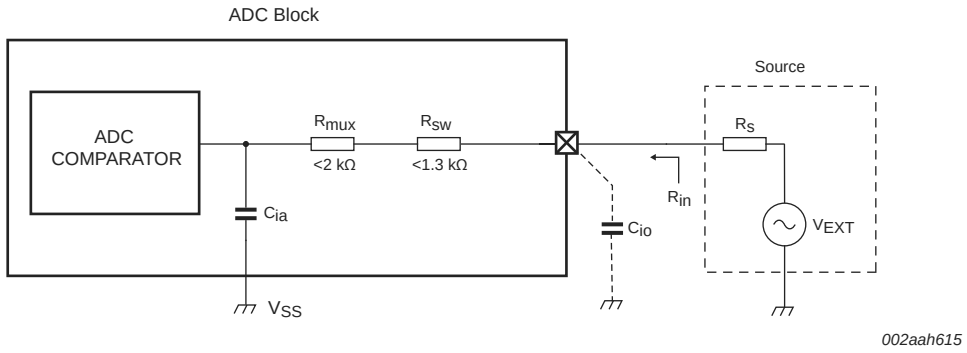

Fig 29. ADC input channel

The effective input impedance, R_{in}, seen by the external voltage source, V_{EXT}, is the parallel impedance of $((1/f_s \times C_{ia}) + R_{mux} + R_{sw})$ and $(1/f_s \times C_{io})$, and can be calculated using Equation 1 with

f_s = sampling frequency

C_{ia} = ADC analog input capacitance

R_{mux} = analog mux resistance

R_{sw} = switch resistance

C_{io} = pin capacitance

$$R_{in} = \left(\frac{1}{f_s \times C_{ia}} + R_{mux} + R_{sw}\right) \parallel \left(\frac{1}{f_s \times C_{io}}\right) \quad (1)$$

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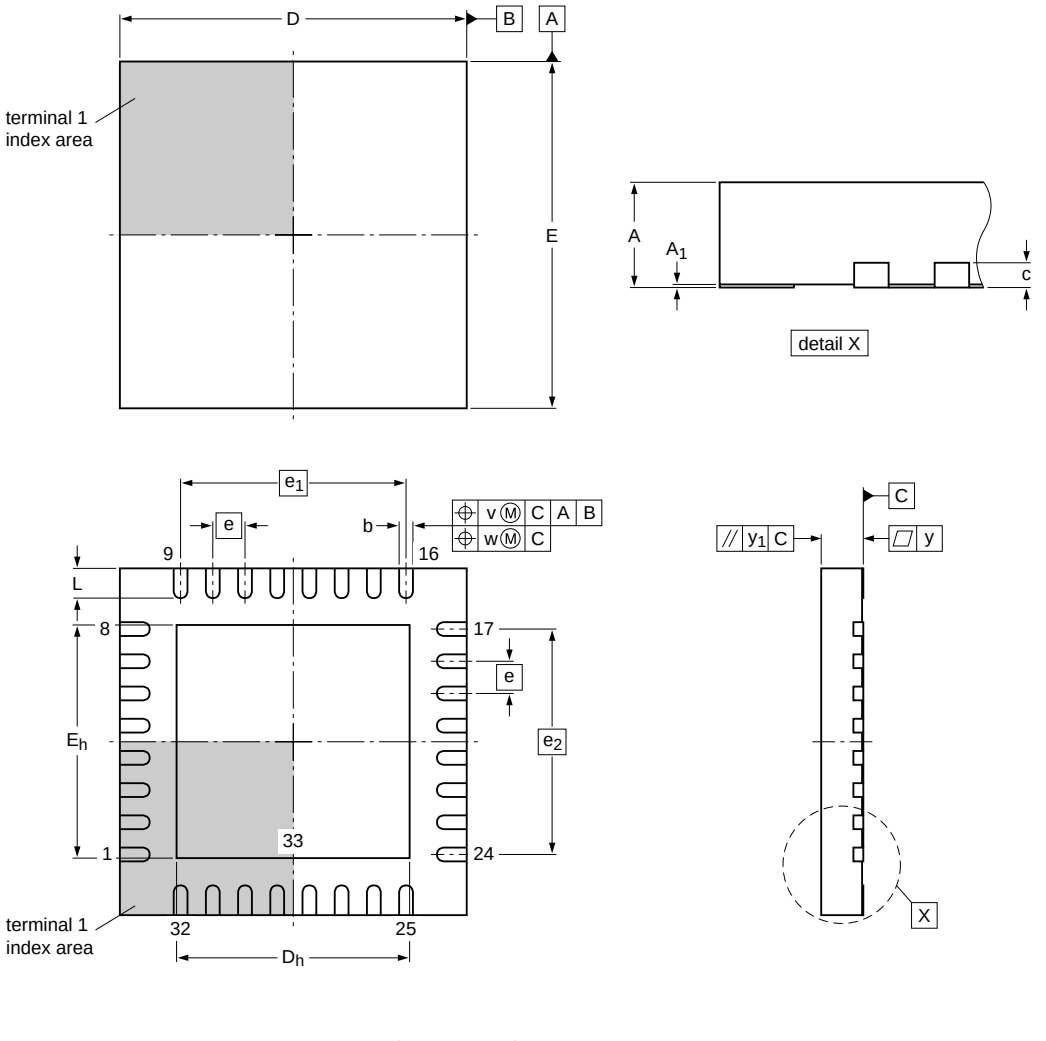
12. Package outline

HVQFN33: plastic thermal enhanced very thin quad flat package; no leads; 33 terminals; body 7 x 7 x 0.85 mm



Dimensions

Unit		$A^{(1)}$	A_1	b	c	$D^{(1)}$	D_h	$E^{(1)}$	E_h	e	e_1	e_2	L	v	w	y	y_1
	max	1.00	0.05	0.35		7.1	4.85	7.1	4.85				0.75				
mm	nom	0.85	0.02	0.28	0.2	7.0	4.70	7.0	4.70	0.65	4.55	4.55	0.60	0.1	0.05	0.08	0.1
	min	0.80	0.00	0.23		6.9	4.55	6.9	4.55				0.45				

Note

1. Plastic or metal protrusions of 0.075 mm maximum per side are not included.

hvqfn33_po

Outline version	References				European projection	Issue date
	IEC	JEDEC	JEITA			
		- - -				~~09-03-17~~ 09-03-23

Fig 30. Package outline HVQFN33 (7 x 7 x 0.85 mm)

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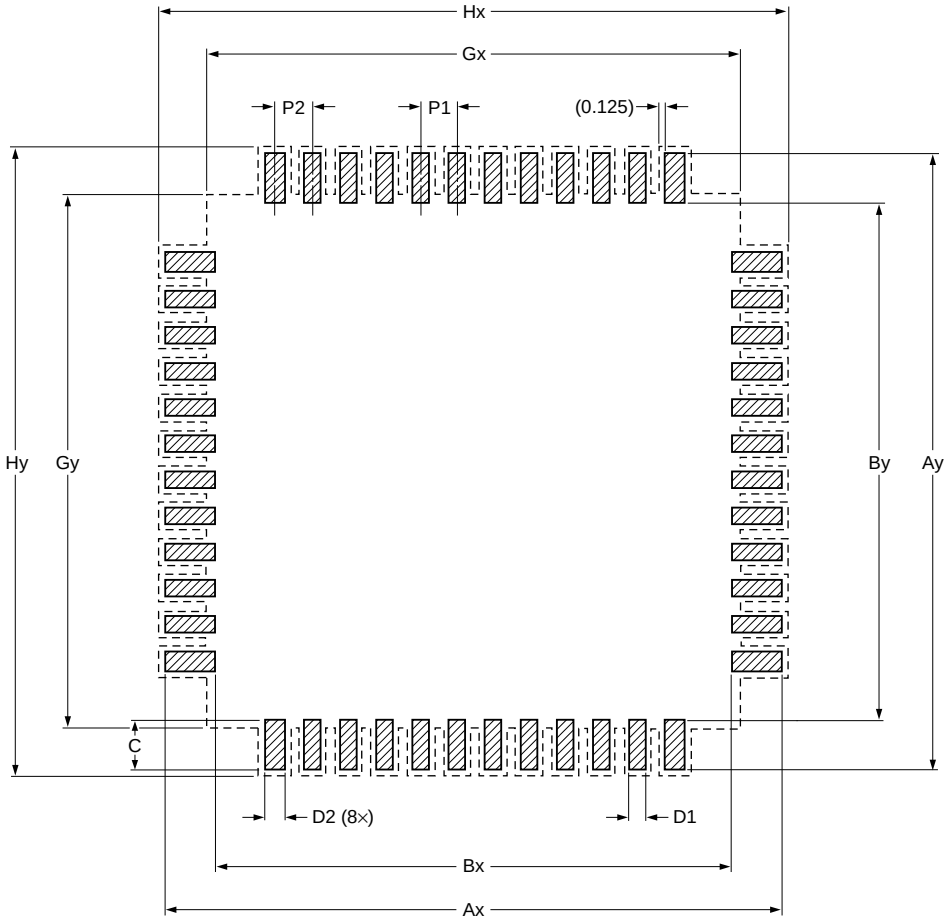
Footprint information for reflow soldering of LQFP48 package **SOT313-2**



Generic footprint pattern

Refer to the package outline drawing for actual layout

solder land

occupied area

DIMENSIONS in mm

P1	P2	Ax	Ay	Bx	By	C	D1	D2	Gx	Gy	Hx	Hy
0.500	0.560	10.350	10.350	7.350	7.350	1.500	0.280	0.500	7.500	7.500	10.650	10.650

sot313-2_fr

Fig 34. Reflow soldering for the LQFP48 package

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15. Revision history

Table 20. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
LPC11E1X v.1.1	20130924	Product data sheet	-	LPC11E1X v.1
Modifications:	• Parameters t_{er} and f_{clk} removed in Table 10. • Table 3: Added “5 V tolerant pad” to $\overline{\text{RESET}}$/PIO0_0 table note. • Table 7: Removed BOD interrupt level 0. • Added Section 11.5 “ADC effective input impedance”. • Programmable glitch filter is enabled by default. See Section 7.7.1. • Table 5 “Static characteristics” added Pin capacitance section. • Table 4 “Limiting values”: – Updated V_{DD} min and max. – Updated V_I conditions. • Table 10 “EEPROM characteristics”: Changed the t_{prog} from 1.1 ms to 2.9 ms; the EEPROM IAP always does an erase and program, thus the total program time is $t_{er} + t_{prog}$.			
LPC11E1X v.1	20120220	Product data sheet	-	-

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